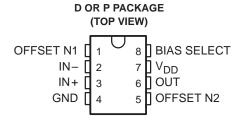
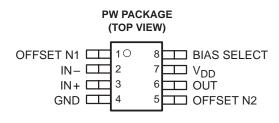
SLOS110A - MAY 1992 - REVISED AUGUST 1994

- Wide Range of Supply Voltages Over Specified Temperature Range:
 - $T_{\Delta} = -40^{\circ}C$ to $85^{\circ}C \dots 2$ V to 8 V
- Fully Characterized at 3 V and 5 V
- Single-Supply Operation
- Common-Mode Input-Voltage Range Extends Below the Negative Rail and up to V_{DD} -1 V at 25°C
- Output Voltage Range Includes Negative Rail

- High Input Impedance . . . $10^{12} \Omega$ Typ
- Low Noise . . . 25 nV/√Hz Typically at f = 1 kHz (High-Bias Mode)
- ESD-Protection Circuitry
- Designed-In Latch-Up Immunity
- Bias-Select Feature Enables Maximum Supply Current Range From 17 μA to 1.5 mA at 25°C





description

The TLV2341 operational amplifier has been specifically developed for low-voltage, single-supply applications and is fully specified to operate over a voltage range of 2 V to 8 V. The device uses the Texas Instruments silicon-gate LinCMOS™ technology to facilitate low-power, low-voltage operation and excellent offset-voltage stability. LinCMOS™ technology also enables extremely high input impedance and low bias currents allowing direct interface to high-impedance sources.

The TLV2341 offers a bias-select feature, which allows the device to be programmed with a wide range of different supply currents and therefore different levels of ac performance. The supply current can be set at 17 μ A, 250 μ A, or 1.5 mA, which results in slew-rate specifications between 0.02 and 2.1 V/ μ s (at 3 V).

The TLV2341 operational amplifiers are especially well suited to single-supply applications and are fully specified and characterized at 3-V and 5-V power supplies. This low-voltage single-supply operation combined with low power consumption makes this device a good choice for remote, inaccessible, or portable battery-powered applications. The common-mode input range includes the negative rail.

The device inputs and outputs are designed to withstand –100-mA currents without sustaining latch-up. The TLV2341 incorporates internal ESD-protection circuits that prevents functional failures at voltages up to 2000 V as tested under MIL-STD 883 C, Methods 3015.2; however, care should be exercised in handling these devices as exposure to ESD may result in the degradation of the device parametric performance.

AVAILABLE OPTIONS

		Р	PACKAGED DEVICES				
TA	V _{IO} max AT 25°C	SMALL OUTLINE (D)	PLASTIC DIP (P)	TSSOP (PW)	CHIP FORM (Y)		
-40°C to 85°C	8 mV	TLV2341ID	TLV2341IP	TLV2341IPWLE	TLV2341Y		

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLV2341IDR). The PW package is only available left-end taped and reeled (e.g., TLV2341IPWLE).

LinCMOS is a trademark of Texas Instruments Incorporated.



bias-select feature

The TLV2342 offers a bias-select feature that allows the user to select any one of three bias levels, depending on the level of performance desired. The tradeoffs between bias levels involve ac performance and power dissipation (see Table 1).

MODE **TYPICAL PARAMETER VALUES MEDIUM BIAS** UNIT **HIGH BIAS LOW BIAS** $T_A = 25^{\circ}C$, $V_{DD} = 3 V$ $R_L = 10 \text{ k}\Omega$ $R_L = 100 \text{ k}\Omega$ $R_L = 1 M\Omega$ Power dissipation 975 195 15 μW P_D SR Slew rate 2.1 0.38 0.02 V/μs nV/√Hz ٧n Equivalent input noise voltage at f = 1 kHz 25 32 68 Unity-gain bandwidth 790 300 27 kHz B₁ Phase margin 46° 39° 34° AVD Large-signal differential voltage amplification 11 83 400 V/mV

Table 1. Effect of Bias Selection on Performance

bias selection

Bias selection is achieved by connecting BIAS SELECT to one of three voltage levels (see Figure 1). For medium-bias applications, it is recommended that the bias-select pin be connected to the midpoint between the supply rails. This procedure is simple in split-supply applications since this point is ground. In single-supply applications, the medium-bias mode necessitates using a voltage divider as indicated in Figure 1. The use of large-value resistors in the voltage divider reduces the current drain of the divider from the supply line. However, large-value resistors used in conjunction with a large-value capacitor require significant time to charge up to the supply midpoint after the supply is switched on. A voltage other than the midpoint may be used if it is within the voltages specified in the following table.

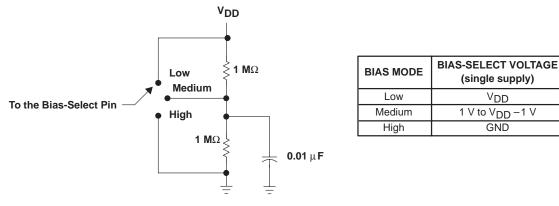


Figure 1. Bias Selection for Single-Supply Applications



SLOS110A - MAY 1992 - REVISED AUGUST 1994

high-bias mode

In the high-bias mode, the TLV2341 series feature low offset voltage drift, high input impedance, and low noise. Speed in this mode approaches that of BiFET devices but at only a fraction of the power dissipation.

medium-bias mode

The TLV2341 in the medium-bias mode features a low offset voltage drift, high input impedance, and low noise. Speed in this mode is similar to general-purpose bipolar devices but power dissipation is only a fraction of that consumed by bipolar devices.

low-bias mode

In the low-bias mode, the TLV2341 features low offset voltage drift, high input impedance, extremely low power consumption, and high differential voltage gain.

ORDER OF CONTENTS

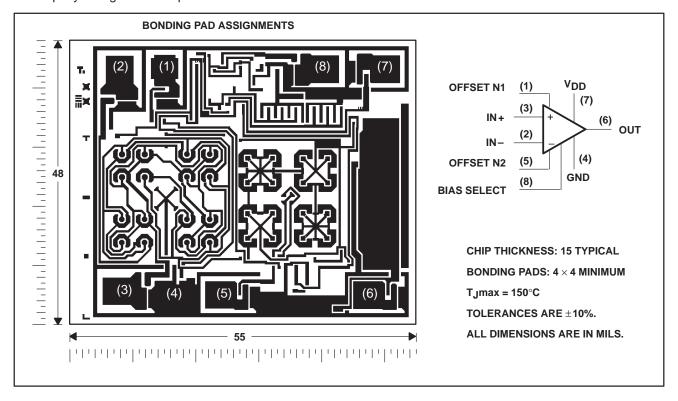
TOPIC	BIAS MODE
Schematic	all
Absolute maximum ratings	all
Recommended operating conditions	all
Electrical characteristics Operating characteristics Typical characteristics	high (Figures 2 – 31)
Electrical characteristics Operating characteristics Typical characteristics	medium (Figures 32 – 61)
Electrical characteristics Operating characteristics Typical characteristics	low (Figures 62 – 91)
Parameter measurement information	all
Application information	all

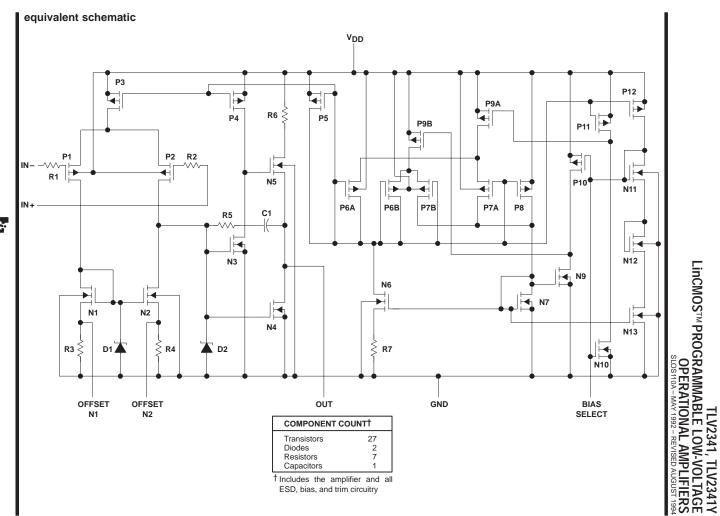


SLOS110A - MAY 1992 - REVISED AUGUST 1994

TLV2341Y chip information

This chip, when properly assembled, displays characteristics similar to the TLV2341. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.





SLOS110A – MAY 1992 – REVISED AUGUST 1994

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{DD} (see Note 1)	8 V
Differential input voltage (see Note 2)	
Input voltage range, V _I (any input)	0.3 V to V _{DD}
Input current, I _I	±5 mĀ
Output current, IO	±30 mA
Duration of short-circuit current at (or below) T _A = 25°C (see Note 3)	unlimited
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	–40°C to 85°C
Storage temperature range	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may effect device reliability.

- NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.
 - 2. Differential voltages are at the noninverting input with respect to the inverting input.
 - 3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 85°C POWER RATING
D	725 mW	5.8 mW/°C	377 mW
Р	1000 mW	8.0 mW/°C	520 mW
PW	525 mW	4.2 mW/°C	273 mW

recommended operating conditions

		MIN	MAX	UNIT
Supply voltage, V _{DD}		2	8	V
	V _{DD} = 3 V	-0.2	1.8	V
Common-mode input voltage, V _{IC}	V _{DD} = 5 V	-0.2	3.8	V
Operating free-air temperature, TA		-40	85	°C



HIGH-BIAS MODE

electrical characteristics at specified free-air temperature

		7507				TLV2	3411			
	PARAMETER	TEST CONDITIONS	T _A †	V	DD = 3 \	/	V	DD = 5 \	/	UNIT
		Constitutions		MIN	TYP	MAX	MIN	TYP	MAX	
Vio	Input offset voltage	V _O = 1 V, V _{IC} = 1 V,	25°C		0.6	8		1.1	8	mV
۷IO	input onset voltage	$R_S = 50 \Omega$, $R_L = 10 kΩ$	Full range			10			10	IIIV
αVIO	Average temperature of input offset voltage		25°C to 85°C		2.7			2.7		μV/°C
lio	Input offset current (see Note 4)	V _O = 1 V,	25°C		0.1			0.1		pА
ΙΟ	input onset current (see Note 4)	V _{IC} = 1 V	85°C		22	1000		24	1000	рA
liΒ	Input bias current (see Note 4)	V _O = 1 V,	25°C		0.6			0.6		pА
'ID	input blue current (see Note 4)	V _{IC} = 1 V	85°C		175	2000		200	2000	P/ \
	Common-mode input voltage range	0500	-0.2	-0.3		-0.2	-0.3		V	
			25°C	to 2	to 2.3		to 4	to 4.2		V
VICR	(see Note 5)			-0.2			-0.2			
			Full range	to			to			V
				1.8			3.8			
Vон	High-level output voltage	$V_{IC} = 1 \text{ V},$ $V_{ID} = 100 \text{ mV},$ $I_{OH} = -1 \text{ mA}$	25°C	1.75	1.9		3.2	3.7		V
VOH	riigii-ievei output voitage		Full range	1.7			3			V
.,	A section of the section of	V _{IC} = 1 V,	25°C		120	150		90	150	
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 1 \text{ mA}$	Full range			190			190	mV
Δ	Large-signal differential	V _{IC} = 1 V,	25°C	3	11		5	23		V/mV
AVD	voltage amplification	R_L = 10 kΩ, See Note 6	Full range	2			3.5			V/IIIV
CMDD	Common mode rejection ratio	V _O = 1 V,	25°C	65	78		65	80		dB
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}$ min, R _S = 50 Ω	Full range	60			60			UD
ka. :-	Supply-voltage rejection ratio	V _{IC} = 1 V,	25°C	70	95		70	95		4D
ksvr	$(\Delta V_{DD}/\Delta V_{IO})$	$V_O = 1 V$, $R_S = 50 \Omega$	Full range	65			65			dB
I _I (SEL)	Bias select current	VI(SEL) = 0	25°C		-1.2			-1.4		μΑ
	Supply current	V _O = 1 V, V _{IC} = 1 V,	25°C		325	1500		675	1600	
IDD	Supply current	No load	Full range			2000			2200	μΑ

†Full range is –40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.
6. At V_{DD} = 5 V, V_O = 0.25 V to 2 V; at V_{DD} = 3 V, V_O = 0.5 V to 1.5 V.



HIGH-BIAS MODE

operating characteristics at specified free-air temperature, $V_{DD} = 3 V$

	PARAMETER		TEST CONDITIONS		TLV2341I			UNIT
	PARAMETER	TEST	CNDITIONS	TA	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	V _{IC} = 1 V, R _L = 10 kΩ,	V _{I(PP)} = 1 V,	25°C		2.1		V/µs
J N	Siew rate at unity gain	See Figure 92		85°C		1.7		ν/μδ
V _n	Equivalent input noise voltage	f = kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
_	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 10 \text{ k}\Omega$,	C _L = 20 pF,	25°C		170		kHz
ВОМ	Maximum output-swing bandwidth		See Figure 92	85°C		145		NI IZ
В.	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		790		kHz
B ₁	Offity-gairt baridwidth	$R_L = 10 \text{ k}\Omega$,	See Figure 94	85°C		690		KIIZ
		V _I = 10 mV,	f = B ₁ ,	-40°C		53°		
φm	Phase margin	$C_L = 20 pF$,		25°C		49°		
		See Figure 94		85°C		47°		

operating characteristics at specified free-air temperature, V_{DD} = 5 V

	PARAMETER	TEST (TEST CONDITIONS			TLV2341I		
	PARAMETER	TEST	CNDITIONS	TA	MIN	TYP	MAX	UNIT
	Slew rate at unity gain	V _{IC} = 1 V,	V((DD) = 1 V	25°C		3.6		
SR		$R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 92	V _{I(PP)} = 1 V	85°C		2.8		\//uo
			V//==> = 2.5.V/	25°C		2.9		V/μs
			$V_{I(PP)} = 2.5 \text{ V}$	85°C		2.3		1 1
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
D	Maximum autout auting handwidth	Vo = VoH,	$C_1 = 20 \text{ pF},$	25°C		320		kHz
ВОМ	Maximum output-swing bandwidth	$R_L = 10 \text{ k}\Omega$,	See Figure 92	85°C		250		K MZ
В.	I laite agin bonderidth	V _I = 10 mV,	$C_1 = 20 \text{ pF},$	25°C		1.7		MHz
B ₁	Unity-gain bandwidth	$R_L = 10 \text{ k}\Omega$,	See Figure 94	85°C		1.2		IVITZ
		V _I = 10 mV,	f = B ₁ ,	-40°C		49°		
φm	Phase margin	$C_L = 20 pF$,	$R_L = 10 \text{ k}\Omega$,	25°C		46°		
		See Figure 94		85°C		43°		

HIGH-BIAS MODE

electrical characteristics, $T_A = 25^{\circ}C$

						TLV2	3411			
	PARAMETER	TEST C	CONDITIONS	V	DD = 3 \	/	V	DD = 5 \	/	UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_{O} = 1 V$, $R_{S} = 50 \Omega$,	V _{IC} = 1 V, R _L = 10 kΩ		0.6	8		1.1	8	mV
IIO	Input offset current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.1			0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.6			0.6		рА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 2	-0.3 to 2.3		-0.2 to 4	-0.3 to 4.2		V
VOH	High-level output voltage	V _{IC} = 1 V, I _{OH} = -1 mA	V _{ID} = 100 mV,	1.75	1.9		3.2	3.7		V
VOL	Low-level output voltage	V _{IC} = 1 V, I _{OL} = 1 mA	$V_{ID} = -100 \text{ mV},$		120	150		90	150	mV
A _{VD}	Large-signal differential voltage amplification	V _{IC} = 1 V, See Note 6	$R_L = 10 \text{ k}\Omega$,	3	11		50	23		V/mV
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $R_S = 50 \Omega$	$V_{IC} = V_{ICR}min$,	65	78		65	80		dB
ksvr	Supply-voltage rejection ratio (ΔV _{DD} /ΔV _{IO})	$V_O = 1 V$, $R_S = 50 \Omega$	V _{IC} = 1 V,	70	95		70	95		dB
I _I (SEL)	Bias select current	V _{I(SEL)} = 0			-1.2			-1.4		μΑ
IDD	Supply current	V _O = 1 V, No load	V _{IC} = 1 V,		325	1500		675	1600	μΑ

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

6. At V_{DD} = 5 V, V_O = 0.25 V to 2 V; at V_{DD} = 3 V, V_O = 0.5 V to 1.5 V.

TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)

Table of Graphs

			FIGURE
VIO	Input offset voltage	Distribution	2,3
ανιο	Input offset voltage temperature coefficient	Distribution	4,5
VOH	High-level output voltage	vs Output current vs Supply voltage vs Temperature	6 7 8
VOL	Low-level output voltage	vs Common-mode input voltage vs Temperature vs Differential input voltage vs Low-level output current	9 10, 12 11 13
A _{VD}	Large-signal differential voltage amplification	vs Supply voltage vs Temperature vs Frequency	14 15 26, 27
I _{IB}	Input bias current	vs Temperature	16
lιο	Input offset current	vs Temperature	16
VIС	Common-mode input voltage	vs Supply voltage	17
IDD	Supply current	vs Supply voltage vs Temperature	18 19
SR	Slew rate	vs Supply voltage vs Temperature	20 21
	Bias select current	vs Supply voltage	22
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	23
B ₁	Unity-gain bandwidth	vs Temperature vs Supply voltage	24 25
φm	Phase margin	vs Supply voltage vs Temperature vs Load capacitance	28 29 30
٧n	Equivalent input noise voltage	vs Frequency	31
	Phase shift	vs Frequency	26, 27



DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

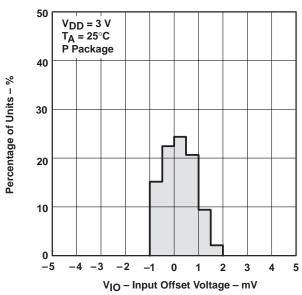


Figure 2

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

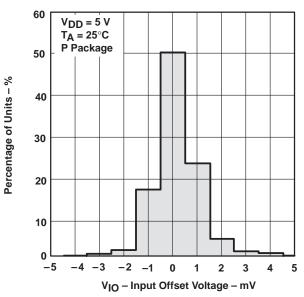
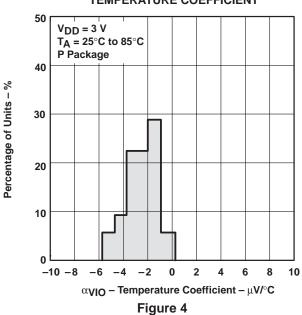
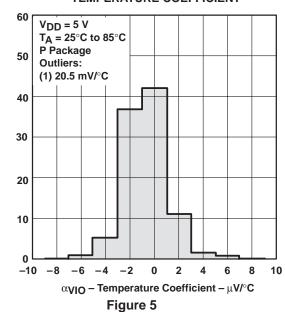


Figure 3

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

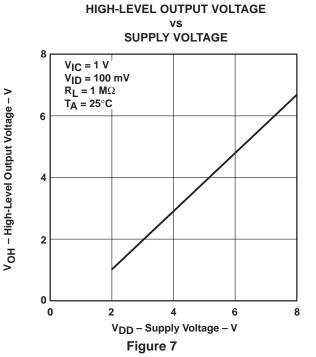


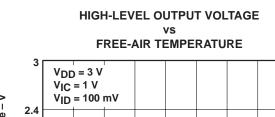
DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

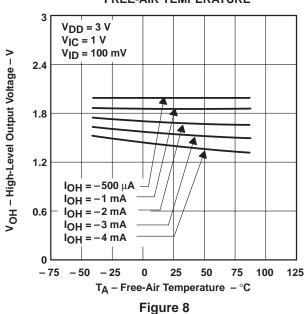


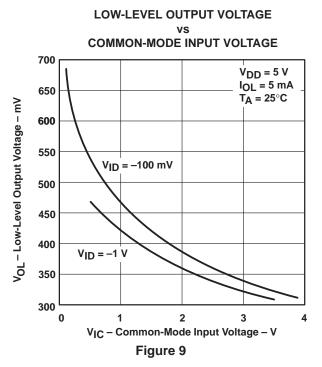
Percentage of Units – %

HIGH-LEVEL OUTPUT VOLTAGE HIGH-LEVEL OUTPUT CURRENT 5 V_{IC} = 1 V $V_{ID} = 100 \text{ mV}$ T_A = 25°C VOH - High-Level Output Voltage - V $V_{DD} = 5 V$ 3 $V_{DD} = 3 V$ 2 0 0 **- 2** - 6 -8 IOH - High-Level Output Current - mA



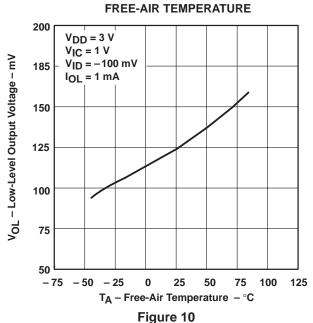




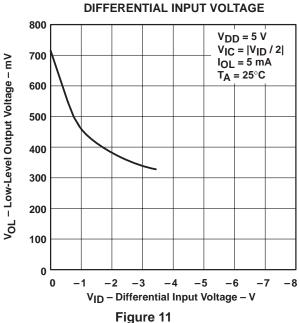


TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)

LOW-LEVEL OUTPUT VOLTAGE vs

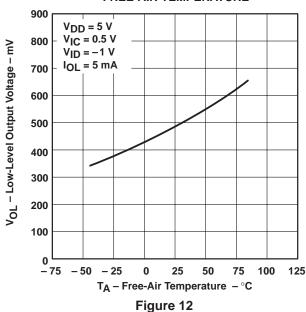


LOW-LEVEL OUTPUT VOLTAGE VS

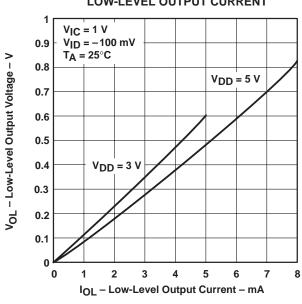


LOW-LEVEL OUTPUT VOLTAGE

FREE-AIR TEMPERATURE



LOW-LEVEL OUTPUT VOLTAGE vs LOW-LEVEL OUTPUT CURRENT



LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION vs

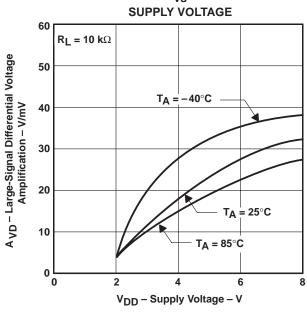


Figure 14

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION vs

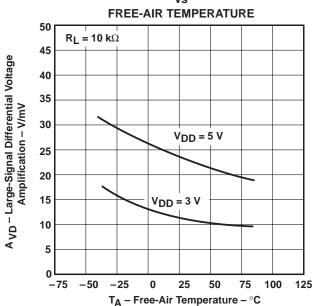
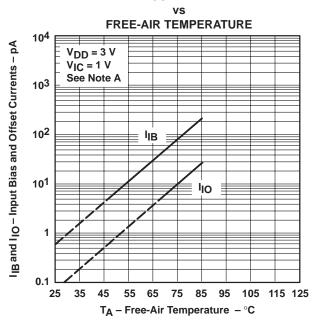


Figure 15

INPUT BIAS CURRENT AND INPUT OFFSET CURRENT



NOTE: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

Figure 16

V_{IC} – Common-Mode Input Voltage – V

COMMON-MODE INPUT VOLTAGE POSITIVE LIMIT

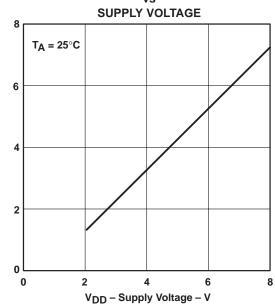
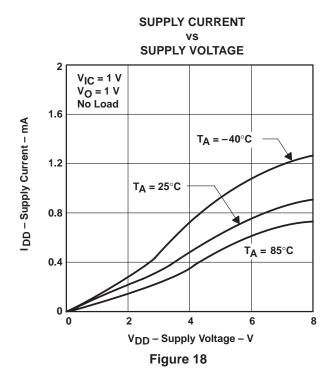


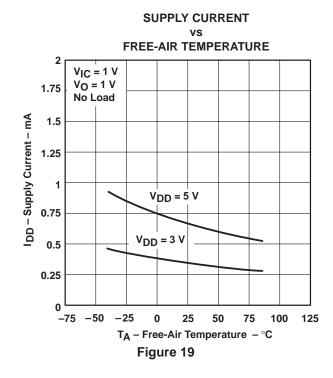
Figure 17

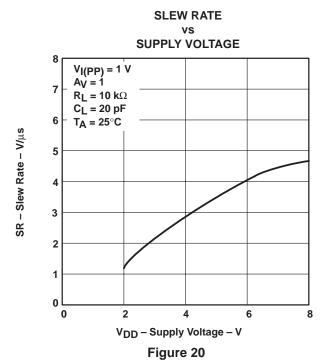


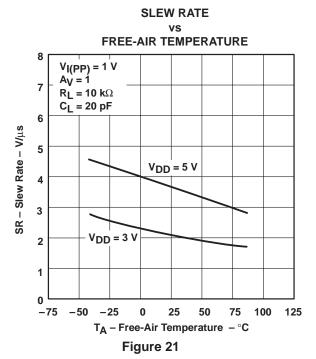


TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)





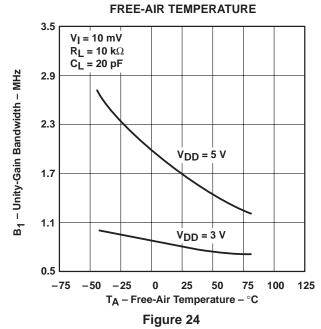




BIAS SELECT CURRENT VS SUPPLY VOLTAGE -3 TA = 25°C VI(SEL) = 0 -1.8 -0.6 0 2 4 VDD - Supply Voltage - V

UNITY-GAIN BANDWIDTH vs

Figure 22



MAXIMUM PEAK-TO-PEAK OUTPUT VOLTAGE

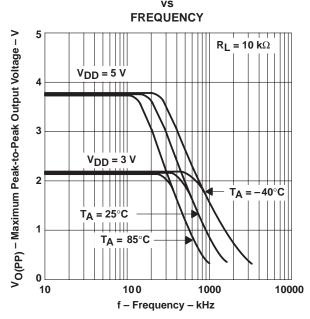
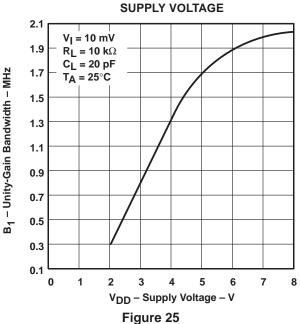


Figure 23

UNITY-GAIN BANDWIDTH vs



TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

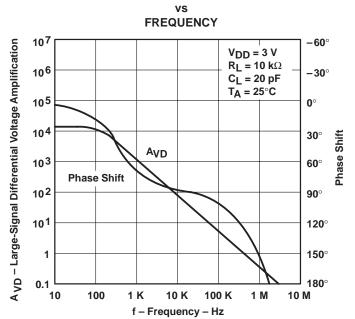


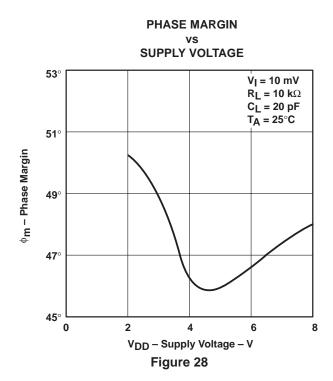
Figure 26

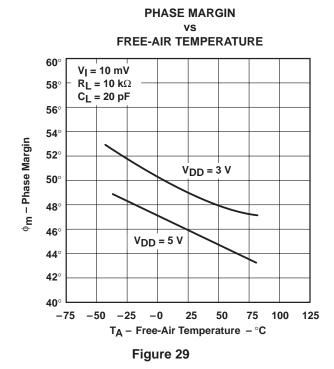
LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

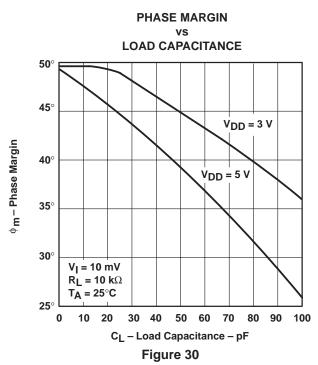
vs **FREQUENCY** 107 -60° A VD - Large-Signal Differential Voltage Amplification $V_{DD} = 5 V$ $R_L = 10 \text{ k}\Omega$ 106 -30° $C_L = 20 pF$ $T_A = 25^{\circ}C$ 105 **0**° 104 Phase Shift 30° AVD 103 60° 10² 90° **Phase Shift** 101 120° 150° 1 0.1 180° 10 100 10 k 100 k 10 M 1 k f - Frequency - Hz

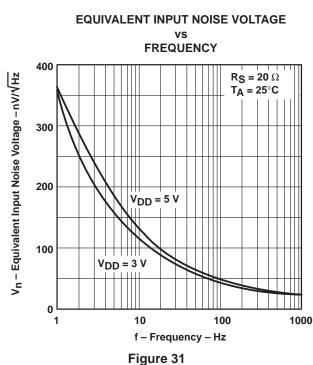
Figure 27











MEDIUM-BIAS MODE

electrical characteristics at specified free-air temperature

		7507				TLV2	3411			
	PARAMETER	TEST CONDITIONS	T _A †	V	DD = 3 \	/	٧	DD = 5 \	<i>'</i>	UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
.,		$V_{O} = 1 V,$ $V_{IC} = 1 V,$	25°C		0.6	8		1.1	8	.,
VIO	Input offset voltage	$R_S = 50 \Omega$, $R_L = 100 k\Omega$	Full range			10			10	mV
αVIO	Average temperature coefficient of input offset voltage		25°C to 85°C		1			1.7		μV/°C
lio	Input offset current (see Note 4)	V _O = 1 V,	25°C		0.1			0.1		pА
10	mput onset current (see Note 4)	V _{IC} = 1 V	85°C		22	1000		24	1000	
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	25°C		0.6			0.6		pА
10	,	V _{IC} = 1 V	85°C		175	2000		200	2000	
			25°C	-0.2	-0.3		-0.2	-0.3		V
	Common-mode input voltage range		25 C	to 2	to 2.3		to 4	to 4.2		V
VICR	(see Note 5)			-0.2			-0.2			
			Full range	to			to			V
				1.8			3.8			
	High level cutout voltage	$V_{IC} = 1 \text{ V},$ $V_{ID} = 100 \text{ mV},$ $I_{OH} = -1 \text{ mA}$	25°C	1.75	1.9		3.2	3.9		V
VOH	High-level output voltage		Full range	1.7			3			V
\/o:	Low-level output voltage	$V_{IC} = 1 \text{ V},$ $V_{ID} = -100 \text{ mV},$	25°C		115	150		95	150	mV
VOL	Low-level output voltage	$I_{OL} = 1 \text{ mA}$	Full range			190			190	IIIV
Δ=	Large-signal differential	$V_{IC} = 1 \text{ V},$ $R_L = 100 \text{ k}\Omega,$	25°C	25	83		25	170		V/mV
AVD	voltage amplification	See Note 6	Full range	15			15			V/IIIV
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $V_{IC} = V_{ICR}min$,	25°C	65	92		65	91		dB
CIVIKK	Common-mode rejection ratio	$R_S = 50 \Omega$	Full range	60			60			иь
kovin	Supply-voltage rejection ratio	V _{IC} = 1 V, V _O = 1 V,	25°C	70	94		70	94		4D
ksvr	$(\Delta V_{DD}/\Delta V_{IO})$	$R_S = 50 \Omega$	Full range	65			65			dB
I(SEL)	Bias select current	VI(SEL) = 0	25°C		-100			-130		nA
Inc	Supply current	V _O = 1 V,	25°C		65	250		105	280	,, ^
IDD	очрріў сипені	V _{IC} = 1 V, No load	Full range			360			400	μΑ

[†] Full range is –40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

- 5. This range also applies to each input individually.
 6. At V_{DD} = 5 V, V_O = 0.25 V to 2 V; at V_{DD} = 3 V, V_O = 0.5 V to 1.5 V.



MEDIUM-BIAS MODE

operating characteristics at specified free-air temperature, $V_{DD} = 3 V$

	DADAMETED	TEST CO.	NDITIONS	т.	TLV2341I			UNIT
	PARAMETER	TEST CO	NUTTONS	TA	MIN	TYP	MAX	UNII
SR	Slew rate at unity gain	$V_{IC} = 1 \text{ V},$ $R_L = 100 \text{ k}\Omega,$	V _I (PP) = 1 V,	25°C		0.38		V/µs
SIX .	Siew rate at unity gain	See Figure 92	OL = 20 pi ,	85°C		0.29		ν/μ5
V _n	Equivalent input noise voltage	f = kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz
Pari	Post Maximum output swing bandwidth		C _L = 20 pF,	25°C		34		kHz
Вом	Maximum output-swing bandwidth	$R_L = 100 \text{ k}\Omega$,	See Figure 92	85°C		32		KHZ
В.	Unity gain handwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		300		kHz
B ₁	Unity-gain bandwidth	$R_L = 100 \text{ k}\Omega$,	See Figure 94	85°C		235		KHZ
		V _I = 10 mV,	f = B ₁ ,	-40°C		42°		
φm	Phase margin	$C_L = 20 pF$,	$R_L = 100 \text{ k}\Omega$,	25°C		39°		
		See Figure 94		85°C		36°		

operating characteristics at specified free-air temperature, V_{DD} = 5 V

	DADAMETED	TEST CO.	TA	TLV2341I			UNIT	
PARAMETER		TEST CO	TEST CONDITIONS		MIN	TYP	MAX	UNII
		V _{IC} = 1 V,	V: 1 V	25°C		0.43		
SR	Clay rate at unity gain	$R_L = 100 \text{ k}\Omega$	V _{I(PP)} = 1 V	85°C		0.35		\//ua
J SK	Slew rate at unity gain	C _L = 20 pF, See Figure 92	V:(==) = 2.5.V	25°C		0.40		V/μs
			$V_{I(PP)} = 2.5 \text{ V}$	85°C		0.32		
V _n	Equivalent input noise voltage	f =1 kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz
Pari	Maximum output-swing bandwidth	Vo = VoH,	$C_{I} = 20 \text{ pF},$	25°C		55		kHz
ВОМ	Maximum output-swing bandwidth	$R_L = 100 \text{ k}\Omega$,	See Figure 92	85°C		45		KHZ
В.	Unity gain handwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		525		kHz
B ₁	Unity-gain bandwidth	$R_L = 100 \text{ k}\Omega$,	See Figure 94	85°C		370		KIIZ
	Phase margin	V _I = 10 mV,	f = B ₁ ,	-40°C		43°		
φm		C _L = 20 pF, See Figure 94	$R_L = 100 \text{ k}\Omega$,	25°C		40°		
				85°C		38°		

MEDIUM-BIAS MODE

electrical characteristics, $T_A = 25^{\circ}C$

				TLV2341I						
	PARAMETER		TEST CONDITIONS		V _{DD} = 3 V		V _{DD} = 5 V			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_O = 1 V$, RS = 50 Ω ,	V _{IC} = 1 V, R _L = 100 kΩ		0.6	8		1.1	8	mV
lιο	Input offset current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.1			0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.6			0.6		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 2	-0.3 to 2.3		-0.2 to 4	-0.3 to 4.2		٧
VOH	High-level output voltage	V _{IC} = 1 V, I _{OH} = -1 mA	V _{ID} = 100 mV,	1.75	1.9		3.2	3.9		V
VOL	Low-level output voltage	V _{IC} = 1 V, I _{OL} = 1 mA	$V_{ID} = -100 \text{ mV},$		115	150		95	150	mV
AVD	Large-signal differential voltage amplification	V _{IC} = 1 V, See Note 6	$R_L = 100 \text{ k}\Omega$,	25	83		25	170		V/mV
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $R_S = 50 \Omega$	$V_{IC} = V_{ICR}min,$	65	92		65	91		dB
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{ID})$	$V_O = 1 V$, $R_S = 50 \Omega$	V _{IC} = 1 V,	70	94		70	94		dB
I _I (SEL)	Bias select current	$V_{I(SEL)} = 0$	·		-100			-130		nA
I _{DD}	Supply current	V _O = 1 V, No load	V _{IC} = 1 V,		65	250		105	280	μΑ

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 3 \text{ V}$, $V_{O} = 0.5 \text{ V}$ to 1.5 V.

TYPICAL CHARACTERISTICS (MEDIUM-BIAS MODE)

Table of Graphs

			FIGURE
VIO	Input offset voltage	Distribution	32, 33
ανιο	Input offset voltage temperature coefficient	Distribution	34, 35
VOH	High-level output voltage	vs Output current vs Supply voltage vs Temperature	36 37 38
VOL	Low-level output voltage	vs Common-mode input voltage vs Temperature vs Differential input voltage vs Low-level output current	39 40, 42 41 43
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Temperature vs Frequency	44 45 56, 57
I _{IB}	Input bias current	vs Temperature	46
lιΟ	Input offset current	vs Temperature	46
VIC	Common-mode input voltage	vs Supply voltage	47
IDD	Supply current	vs Supply voltage vs Temperature	48 49
SR	Slew rate	vs Supply voltage vs Temperature	50 51
	Bias select current	vs Supply current	52
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	53
B ₁	Unity-gain bandwidth	vs Temperature vs Supply voltage	54 55
фm	Phase margin	vs Supply voltage vs Temperature vs Load capacitance	58 59 60
Vn	Equivalent input noise voltage	vs Frequency	61
	Phase shift	vs Frequency	56, 57



Percentage of Units – %

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

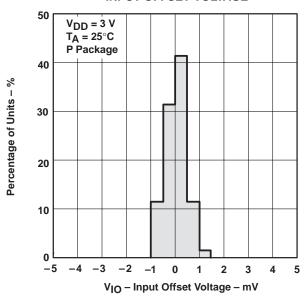


Figure 32

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

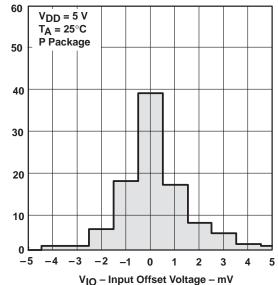
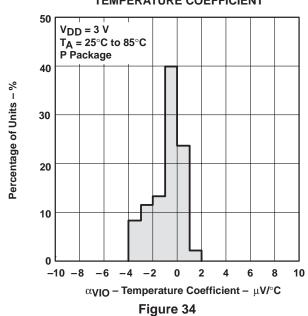
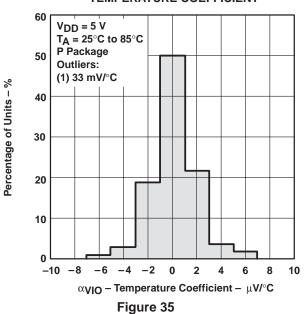


Figure 33

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



VOH - High-Level Output Voltage - V

HIGH-LEVEL OUTPUT VOLTAGE HIGH-LEVEL OUTPUT CURRENT 5 V_{IC} = 1 V V_{ID} = 100 mV T_A = 25°C VOH - High-Level Output Voltage - V $V_{DD} = 5 V$ 3 $V_{DD} = 3 V$ 2 0 0 -2 -4 -6 -8 IOH - High-Level Output Current - mA



HIGH-LEVEL OUTPUT VOLTAGE

vs FREE-AIR TEMPERATURE $V_{DD} = 3 V$ **V_{IC}** = 1 **V** V_{ID} = 100 mV V_{OH} – High-Level Output Voltage – V 2.4 1.8 1.2 $I_{OH} = -500 \,\mu A$ I_{OH} = -1 mA 0.6 $I_{OH} = -2 \text{ mA}$ $I_{OH} = -3 \text{ mA}$ IOH = -4 mA-50 -25 75 100 125 T_A - Free-Air Temperature - °C

Figure 38

HIGH-LEVEL OUTPUT VOLTAGE vs SUPPLY VOLTAGE

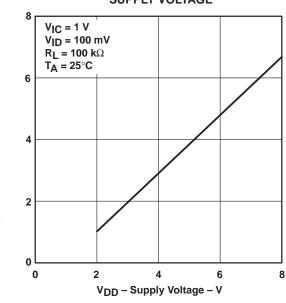
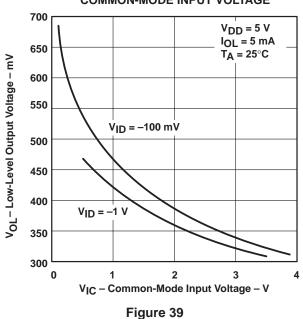
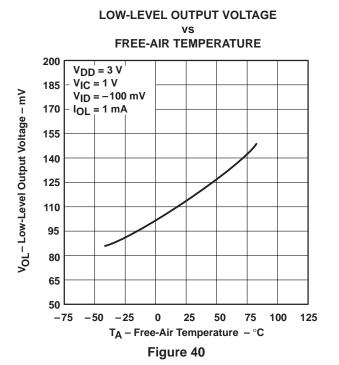
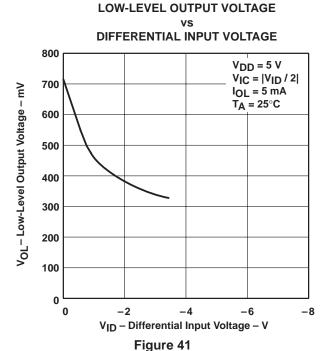


Figure 37

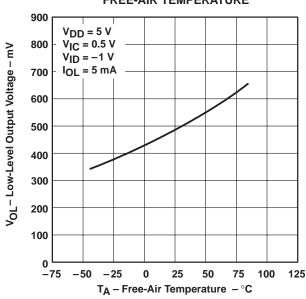
LOW-LEVEL OUTPUT VOLTAGE vs COMMON-MODE INPUT VOLTAGE







LOW-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE



LOW-LEVEL OUTPUT VOLTAGE vs
LOW-LEVEL OUTPUT CURRENT

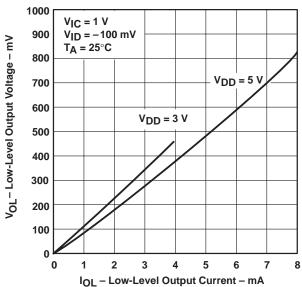
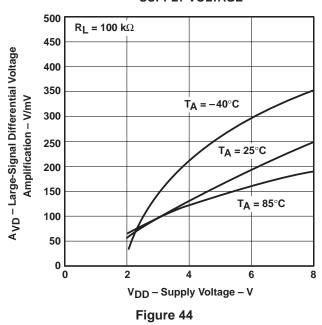


Figure 43

A VD - Large-Signal Differential Voltage

LARGE-SIGNAL **DIFFERENTIAL VOLTAGE AMPLIFICATION** vs SUPPLY VOLTAGE



LARGE-SIGNAL **DIFFERENTIAL VOLTAGE AMPLIFICATION** vs FREE-AIR TEMPERATURE

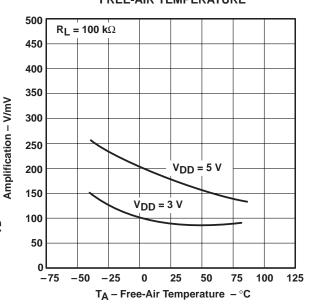
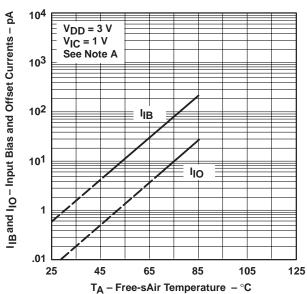


Figure 45

INPUT BIAS CURRENT AND INPUT OFFSET CURRENT vs

FREE-AIR TEMPERATURE



NOTE A: The typical values of input bias current and input offset current below 5 pA are determined mathematically.

COMMON-MODE INPUT VOLTAGE POSITIVE LIMIT vs

SUPPLY VOLTAGE

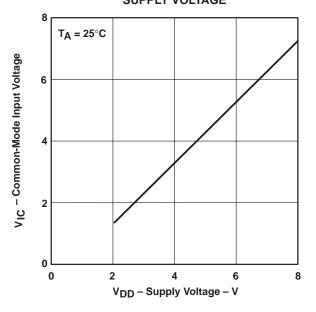
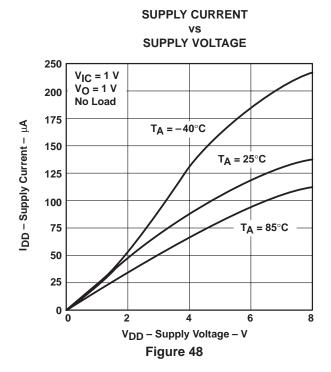
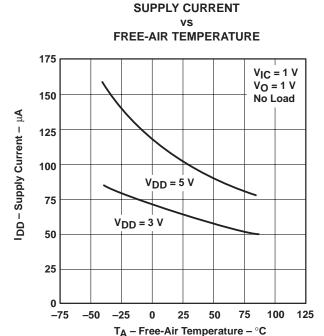


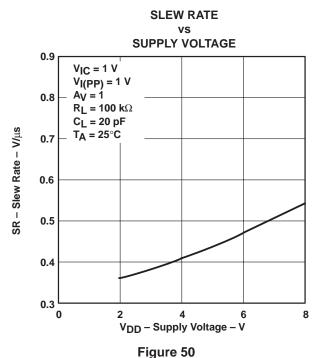
Figure 47

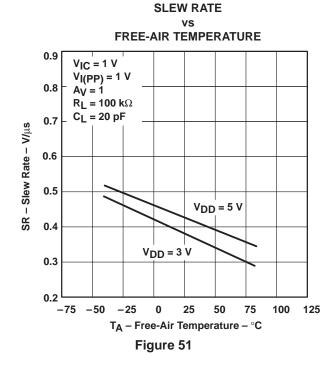


TYPICAL CHARACTERISTICS (MEDIUM-BIAS MODE)







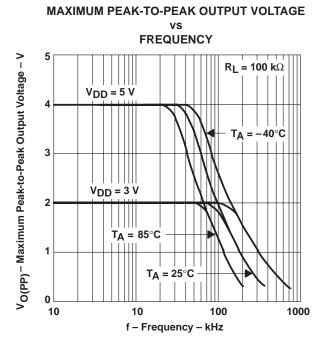


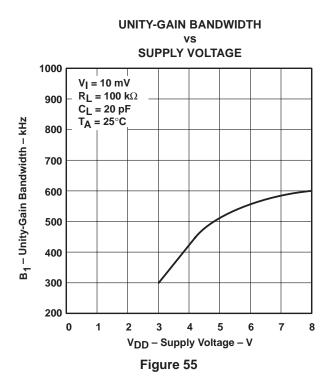
BIAS SELECT CURRENT SUPPLY VOLTAGE -300T_A = 25°C $V_{I(SEL)} = 1/2 V_{DD}$ - 270 - 240 Bias Select Current - nA - 210 - 180 - 150 -120- 90 - 60 -300 o 2 4 8 V_{DD} – Supply Voltage – V

Figure 52

UNITY-GAIN BANDWIDTH FREE-AIR TEMPERATURE 1000 V_I = 10 mV $R_L = 100 \text{ k}\Omega$ 900 $C_{L}^{-} = 20 \text{ pF}$ B₁ - Unity-Gain Bandwidth - kHz 800 700 $V_{DD} = 5 V$ 600 500 400 $V_{DD} = 3 V$ 300 200 -75 -50 75 100 -25 0 25 50 125 T_A – Free-Air Temperature – °C

Figure 54





TYPICAL CHARACTERISTICS (MEDIUM-BIAS MODE)

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

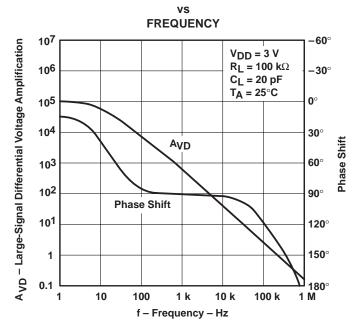


Figure 56

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

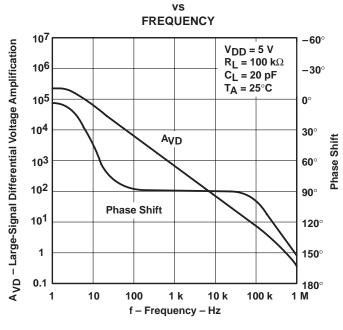
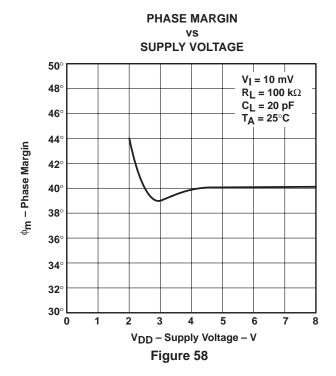
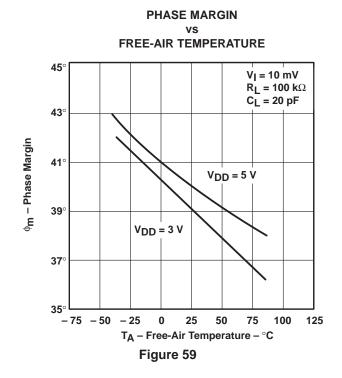
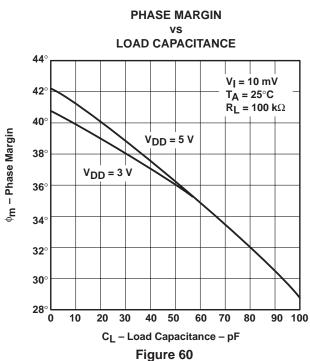


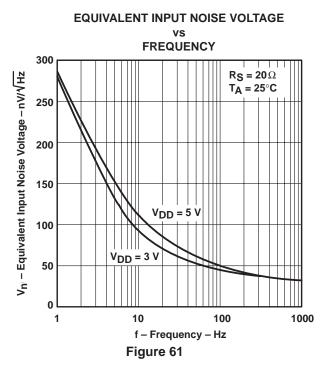
Figure 57











LOW-BIAS MODE

electrical characteristics at specified free-air temperature

		TEOT		TLV2341I						
PARAMETER		TEST CONDITIONS	T _A †	$V_{DD} = 3 V$ $V_{DD} = 5 V$					'	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
V _{IO}	Input offset voltage	V _O = 1 V, V _{IC} = 1 V,	25°C		0.6	8		1.1	8	mV
VIO	input onset voltage	$R_S = 50 \Omega$, $R_L = 1 M\Omega$	Full range			10			10	1117
αVIO	Average temperature of input offset voltage		25°C to 85°C		1			1.1		μV/°C
li o	Input offset current (see Note 4)	V _O = 1 V,	25°C		0.1			0.1		pА
ΙΟ	input onset current (see Note 4)	V _{IC} = 1 V	85°C		22	1000		24	1000	PΑ
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	25°C		0.6			0.6		pА
ID	mpat blas carrein (see Note 4)	V _{IC} = 1 V	85°C		175	2000		200	2000	
				-0.2	-0.3		-0.2	-0.3		
	Common-mode input voltage range (see Note 5)		25°C	to 2	to 2.3		to 4	to 4.2		V
VICR				-0.2	2.0		-0.2	7.2		
			Full range	-0.2 to			-0.2 to			V
				1.8			3.8			
		V _{IC} = 1 V,	25°C	1.75	1.9		3.2	3.8		
VOH	High-level output voltage	$V_{ID} = 100 \text{ mV},$ $I_{OH} = -1 \text{ mA}$	Full range	1.7			3			V
VOL	Low-level output voltage	V _{IC} = 1 V, V _{ID} = -100 mV,	25°C		115	150		95	150	mV
VOL	Low lover output voltage	I _{OL} = 1 mA	Full range			190			190	111.4
Δ. (D.	Large-signal differential	$V_{IC} = 1 V$, $R_{I} = 1 M\Omega$,	25°C	50	400		50	520		V/mV
AVD	voltage amplification	See Note 6	Full range	50			50			V/IIIV
CMRR	Common-mode rejection ratio	V _O = 1 V, V _{IC} = V _{ICR} min,	25°C	65	88		65	94		dB
CIVIKK	Common-mode rejection ratio	VIC = VICRIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII	Full range	60			60			uБ
kovp	Supply-voltage rejection ratio	V _{IC} = 1 V, V _O = 1 V,	25°C	70	86		70	86		dB
ksvr	$(\Delta V_{DD}/\Delta V_{IO})$	$R_S = 50 \Omega$	Full range	65			65			uБ
l(SEL)	Bias select current	VI(SEL) = 0	25°C		10			65		nA
l==	Supply current	V _O = 1 V, V _{IC} = 1 V,	25°C		5	17		10	17	
^I DD	Supply current	No load	Full range			27			27	μΑ

[†] Full range is –40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.
6. At V_{DD} = 5 V, V_{O(PP)} = 0.25 V to 2 V; at V_{DD} = 3 V, V_O = 0.5 V to 1.5 V.

LOW-BIAS MODE

operating characteristics at specified free-air temperature, $V_{DD} = 3 V$

PARAMETER		TEST CONDITIONS		т.	TLV2341I			UNIT
				TA	MIN	TYP	MAX	UNII
SR	Slew rate at unity gain	V _{IC} = 1 V, R _L = 1 MΩ,	V _I (PP) = 1 V,	25°C		0.02		V/µs
J N		See Figure 92	о_ = 20 рг,	85°C		0.02		ν/μδ
Vn	Equivalent input noise voltage	f = kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		68		nV/√Hz
V V		Vo = VoH,	C _L = 20 pF,	25°C		2.5		kHz
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,	See Figure 92	85°C		2		KHZ
В.	Unity gain handwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		27		kHz
B ₁	Unity-gain bandwidth $R_L = 1 M\Omega$, Se		See Figure 94	85°C		21		KIIZ
		V _I = 10 mV,	f = B ₁ ,	-40°C		39°		
φm	Phase margin		$R_L = 1 M\Omega$,	25°C		34°		
		See Figure 94		85°C		28°		

operating characteristics at specified free-air temperature, V_{DD} = 5 V

	DADAMETED	TEST CO.	Ŧ	TLV2341I			UNIT			
PARAMETER		TEST CO	NDITIONS	T _A	MIN	TYP	MAX	UNII		
		V _{IC} = 1 V,	V:1-V	25°C		0.03				
SR	Clay rate at unity gain	$R_L = 1 M\Omega$,	V _{I(PP)} = 1 V	85°C		0.03		\//uo		
J SK	Slew rate at unity gain	C _L = 20 pF, See Figure 92	V:(==) = 2.5.V	25°C		0.03		V/μs		
			$V_{I(PP)} = 2.5 \text{ V}$	85°C		0.02				
Vn	Equivalent input noise voltage	f =1 kHz, See Figure 93	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz		
Pari	Maximum output-swing bandwidth	VO = VOH,	$C_{I} = 20 \text{ pF},$	25°C		5		kHz		
ВОМ	Maximum output-swing bandwidth	$R_L = 1 M\Omega$,			See Figure 92	85°C		4		KΠZ
В.	Unity gain handwidth	V _I = 10 mV,	C _L = 20 pF,	25°C		85		kHz		
B ₁	Unity-gain bandwidth	$R_L = 1 M\Omega$,	See Figure 94	85°C		55		KHZ		
	Phase margin	V _I = 10 mV,	f = B ₁ ,	-40°C		38°				
φm		$C_L = 20 \text{ pF},$	$R_L = 1 M\Omega$,	25°C		34°				
		See Figure 94		85°C		28°				

LOW-BIAS MODE

electrical characteristics, $T_A = 25^{\circ}C$

		TLV2341Y								
PARAMETER		TEST CONDITIONS		V _{DD} = 3 V			V _{DD} = 5 V			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	$V_O = 1 V$, $R_S = 50 \Omega$,	$V_{IC} = 1 V$, $R_L = 1 M\Omega$		0.6	8		1.1	8	mV
I _{IO}	Input offset current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.1			0.1		pA
I _{IB}	Input bias current (see Note 4)	V _O = 1 V,	V _{IC} = 1 V		0.6			0.6		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 2	-0.3 to 2.3		-0.2 to 4	-0.3 to 4.2		V
Vон	High-level output voltage	V _{IC} = 1 V, I _{OH} = -1 mA	V _{ID} = 100 mV,	1.75	1.9		3.2	3.8		V
VOL	Low-level output voltage	V _{IC} = 1 V, I _{OL} = 1 mA	$V_{ID} = -100 \text{ mV},$		115	150		95	150	mV
AVD	Large-signal differential voltage amplification	V _{IC} = 1 V, See Note 6	$R_L = 1 M\Omega$,	50	400		50	520		V/mV
CMRR	Common-mode rejection ratio	$V_O = 1 V$, $R_S = 50 \Omega$	$V_{IC} = V_{ICR}min,$	65	88		65	94		dB
k _{SVR}	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{ID})$	$V_{DD} = 3 \text{ V to 5 V},$ $V_{O} = 1 \text{ V},$	V _{IC} = 1 V, R _S = 50 Ω	70	86		70	86		dB
I _I (SEL)	Bias select current	V _I (SEL) = 0			10			65		nA
I _{DD}	Supply current	V _O = 1 V, No load	V _{IC} = 1 V,		5	17		10	17	μΑ

NOTES: 4. The typical values of input bias current and input offset current below 5 pA are determined mathematically.

5. This range also applies to each input individually.

^{6.} At V_{DD} = 5 V, V_{O} = 0.25 V to 2 V; at V_{DD} = 3 V, V_{O} = 0.5 V to 1.5 V.

TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

Table of Graphs

			FIGURE
VIO	Input offset voltage	Distribution	62, 63
ανιο	Input offset voltage temperature coefficient	Distribution	64, 65
Vон	High-level output voltage	vs Output current vs Supply voltage vs Temperature	66 67 68
VOL	Low-level output voltage	vs Common-mode input voltage vs Temperature vs Differential input voltage vs Low-level output current	69 70, 72 71 73
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Temperature vs Frequency	74 75 86, 87
I _{IB}	Input bias current	vs Temperature	76
liO	Input offset current	vs Temperature	76
VIC	Common-mode input voltage	vs Supply voltage	77
IDD	Supply current	vs Supply voltage vs Temperature	78 79
SR	Slew rate	vs Supply voltage vs Temperature	80 81
	Bias select current	vs Supply current	82
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	83
B ₁	Unity-gain bandwidth	vs Temperature vs Supply voltage	84 85
φm	Phase margin	vs Supply voltage vs Temperature vs Load capacitance	88 89 90
٧n	Equivalent input noise voltage	vs Frequency	91
	Phase shift	vs Frequency	86, 87



TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

Percentage of Units - %

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

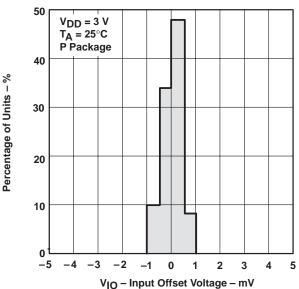


Figure 62

DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE

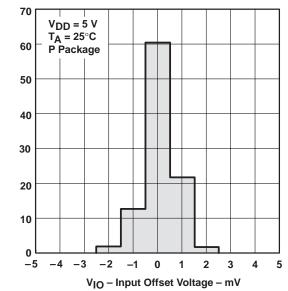
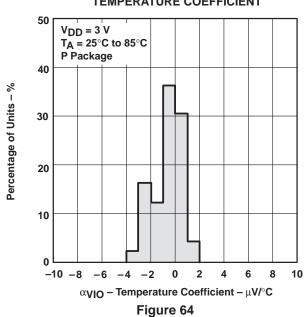
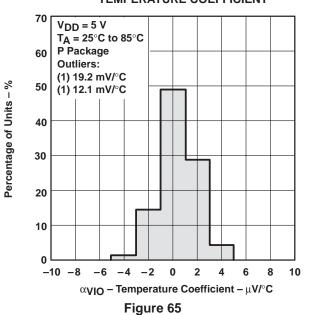


Figure 63

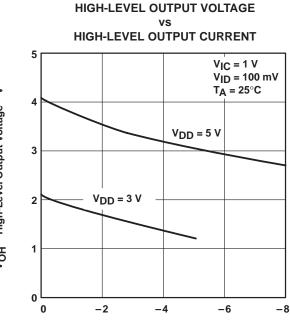
DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

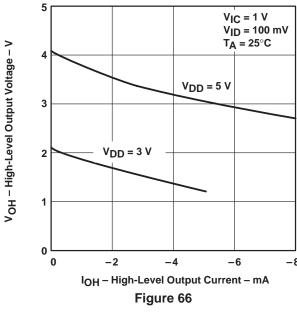


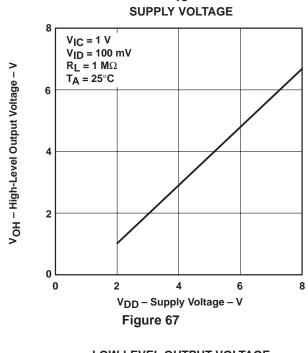
DISTRIBUTION OF TLV2341 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



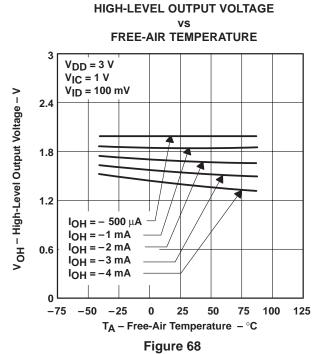
TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

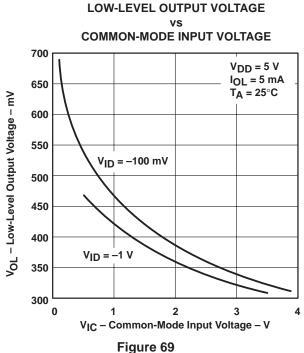






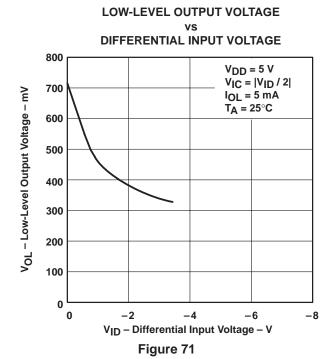
HIGH-LEVEL OUTPUT VOLTAGE





TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

LOW-LEVEL OUTPUT VOLTAGE FREE-AIR TEMPERATURE 200 $V_{DD} = 3 V$ VIC = 1 V 185 $V_{ID}^{ID} = -100 \text{ mV}$ VOL - Low-Level Output Voltage - mV 170 $I_{OL} = 1 \text{ mA}$ 155 140 125 110 95 80 65 50 -50 25 50 -75 -25 0 75 100 125 T_A - Free-Air Temperature - °C Figure 70



LOW-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

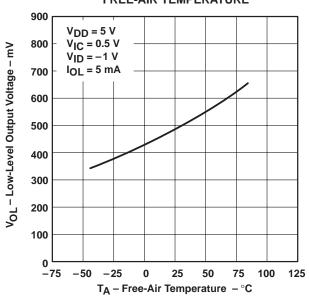


Figure 72

LOW-LEVEL OUTPUT VOLTAGE
vs
LOW-LEVEL OUTPUT CURRENT

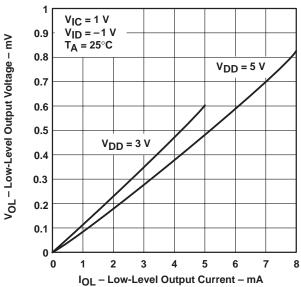
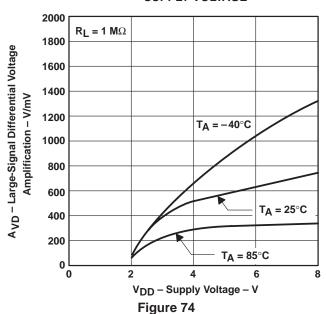


Figure 73

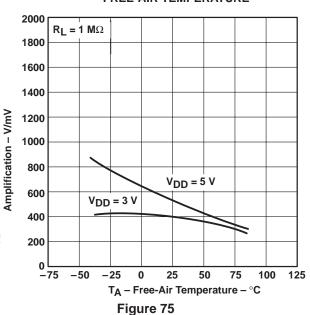
TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

A_{VD} - Large-Signal Differential Voltage

LARGE-SIGNAL **DIFFERENTIAL VOLTAGE AMPLIFICATION** vs SUPPLY VOLTAGE

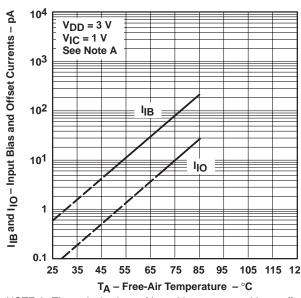


LARGE-SIGNAL **DIFFERENTIAL VOLTAGE AMPLIFICATION** vs FREE-AIR TEMPERATURE



INPUT BIAS CURRENT AND INPUT OFFSET CURRENT

FREE-AIR TEMPERATURE



NOTE A: The typical values of input bias current and input offset current below 5 pA are determined mathematically.

COMMON-MODE INPUT VOLTAGE POSITIVE LIMIT

SUPPLY VOLTAGE

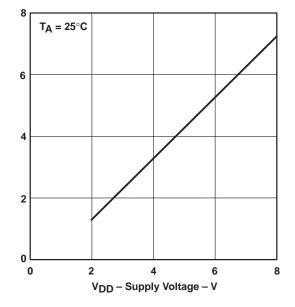


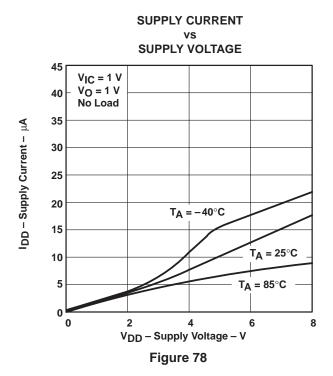
Figure 76 Figure 77

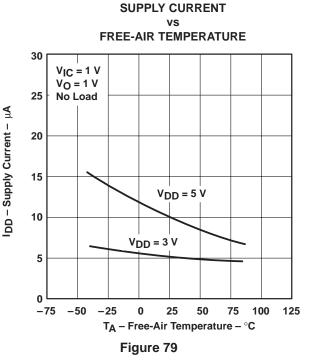
- Common-Mode Input Voltage

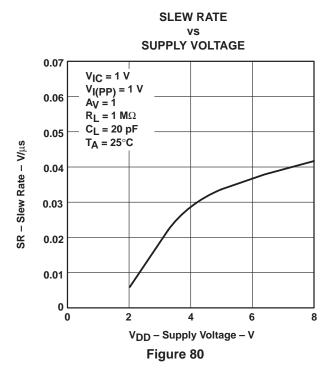
<u>ပ</u>

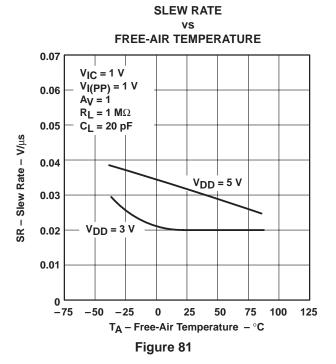


TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

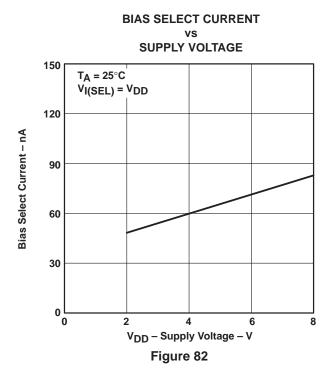


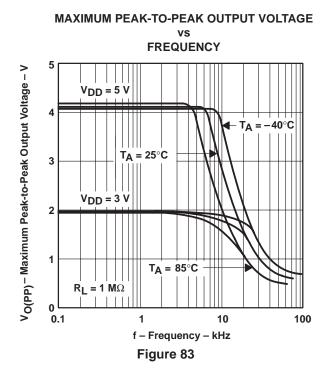


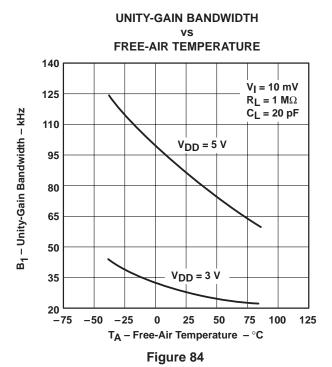


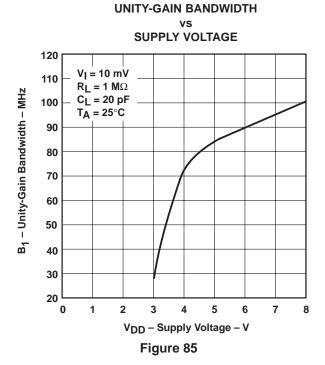


TYPICAL CHARACTERISTICS (LOW-BIAS MODE)









TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

LARGE-SIGNAL DIFFERENTIAL VOLTAGE **AMPLIFICATION AND PHASE SHIFT**

vs **FREQUENCY**

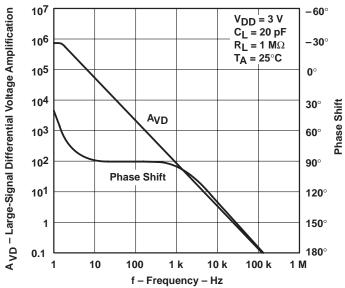


Figure 86

LARGE-SIGNAL DIFFERENTIAL VOLTAGE **AMPLIFICATION AND PHASE SHIFT**

vs **FREQUENCY**

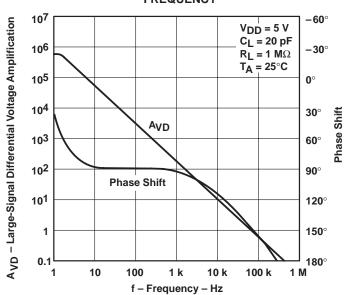
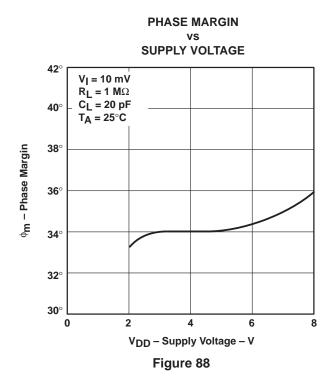
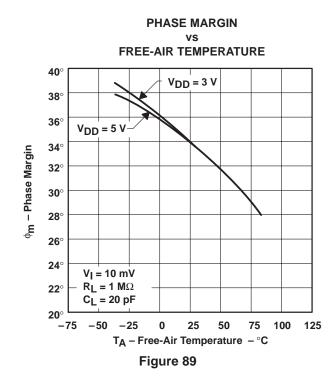


Figure 87



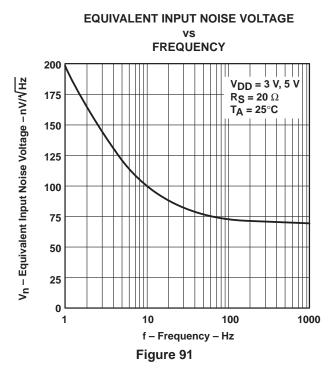
TYPICAL CHARACTERISTICS (LOW-BIAS MODE)





PHASE MARGIN vs **LOAD CAPACITANCE** 40° 38 36° $V_{DD} = 3 V$ **34**° ⁰m − Phase Margin 32° $V_{DD} = 5 V$ 30° 28 26° 24° $V_I = 10 \text{ mV}$ 22° $R_L = 1 M\Omega$ T_A = 25°C 20° 0 20 30 40 50 60 70 80 90 100 C_L - Load Capacitance - pF

Figure 90



PARAMETER MEASUREMENT INFORMATION

single-supply versus split-supply test circuits

Because the TLV2341 is optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

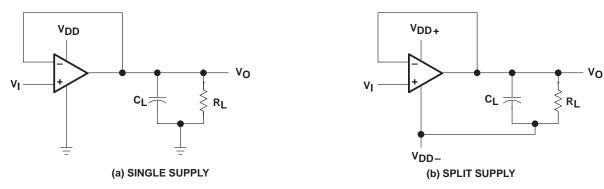


Figure 92. Unity-Gain Amplifier

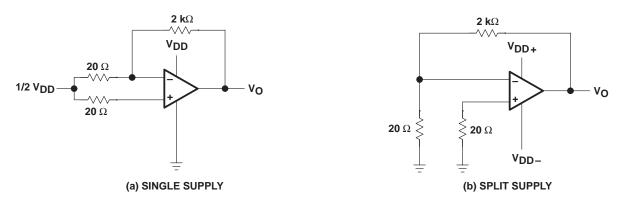


Figure 93. Noise-Test Circuits

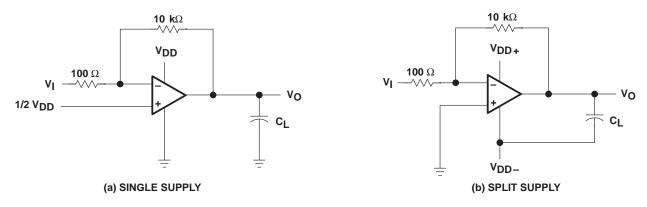


Figure 94. Gain-of-100 Inverting Amplifier



PARAMETER MEASUREMENT INFORMATION

input bias current

Because of the high input impedance of the TLV2341 operational amplifier, attempts to measure the input bias current can result in erroneous readings. The bias current at normal ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 95). Leakages that would otherwise flow to the inputs are shunted away.
- Compensate for the leakage of the test socket by actually performing an input bias current test (using a
 picoammeter) with no device in the test socket. The actual input bias current can then be calculated by
 subtracting the open-socket leakage readings from the readings obtained with a device in the test
 socket.

Many automatic testers as well as some bench-top operational amplifier testers use the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into the test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

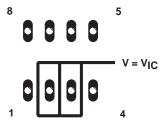


Figure 95. Isolation Metal Around Device Inputs (P package)

low-level output voltage

To obtain low-level supply-voltage operation, some compromise is necessary in the input stage. This compromise results in the device low-level output voltage being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to the Typical Characteristics section of this data sheet.

input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance which can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. These measurements should be performed at temperatures above freezing to minimize error.

full-power response

Full-power response, the frequency above which the operational amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is



PARAMETER MEASUREMENT INFORMATION

generally measured by monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 92. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 96). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

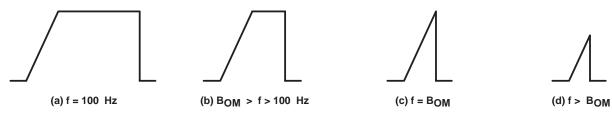


Figure 96. Full-Power-Response Output Signal

test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.

APPLICATION INFORMATION

single-supply operation

While the TLV2341 performs well using dual-power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This includes an input common-mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 2 V, thus allowing operation with supply levels commonly available for TTL and HCMOS.

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. This virtual ground can be generated using two large resistors, but a preferred technique is to use a virtual-ground generator such as the TLE2426. The TLE2426 supplies an accurate voltage equal to V_{DD}/2, while consuming very little power and is suitable for supply voltages of greater than 4 V.

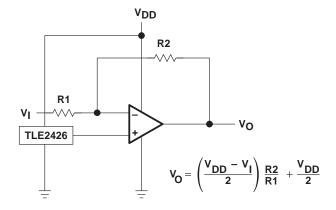


Figure 97. Inverting Amplifier With Voltage Reference



APPLICATION INFORMATION

single-supply operation (continued)

The TLV2341 works well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- Power the linear devices from separate bypassed supply lines (see Figure 98); otherwise, the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive
 decoupling is often adequate; however, RC decoupling may be necessary in high-frequency
 applications.

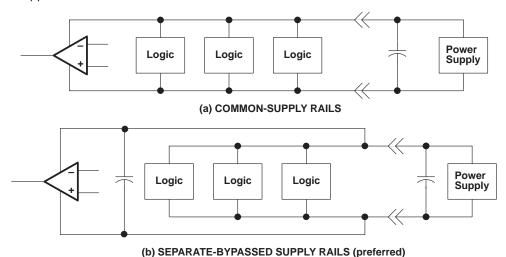


Figure 98. Common Versus Separate Supply Rails

input offset voltage nulling

The TLV2341 offers external input offset null control. Nulling of the input offset voltage can be achieved by adjusting a 25-k Ω potentiometer connected between the offset null terminals with the wiper connected as shown in Figure 99. The amount of nulling range varies with the bias selection. In the high-bias mode, the nulling range allows the maximum offset voltage specified to be trimmed to zero. In low-bias and medium-bias modes, total nulling may not be possible.



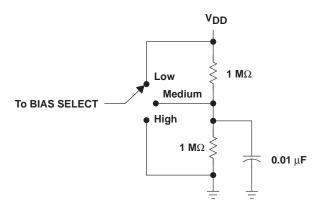
Figure 99. Input Offset Voltage Null Circuit



APPLICATION INFORMATION

bias selection

Bias selection is achieved by connecting the bias-select pin to one of the three voltage levels (see Figure 100). For medium-bias applications, it is recommended that the bias-select pin be connected to the midpoint between the supply rails. This is a simple procedure in split-supply applications, since this point is ground. In single-supply applications, the medium-bias mode necessitates using a voltage divider as indicated. The use of large-value resistors in the voltage divider reduces the current drain of the divider from the supply line. However, large-value resistors used in conjunction with a large-value capacitor require significant time to charge up to the supply midpoint after the supply is switched on. A voltage other than the midpoint may be used if it is within the voltages specified in the following table.



BIAS MODE	BIAS-SELECT VOLTAGE (single supply)
Low	V_{DD}
Medium	1 V to V _{DD} –1 V
High	GND

Figure 100. Bias Selection for Single-Supply Applications

input characteristics

The TLV2341 is specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. The lower the range limit includes the negative rail, while the upper range limit is specified at $V_{DD}-1$ V at $T_{A}=25^{\circ}$ C and at $V_{DD}-1.2$ V at all other temperatures.

The use of the polysilicon-gate process and the careful input circuit design gives the TLV2341 good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically 0.1 μ V/month, including the first month of operation.

Because of the extremely high input impedance and resulting low bias-current requirements, the TLV2341 is well suited for low-level signal processing; however, leakage currents on printed-circuit boards and sockets can easily exceed bias-current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 95 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 101).

The inputs of any unused amplifiers should be tied to ground to avoid possible oscillation.



APPLICATION INFORMATION

input characteristics (continued)

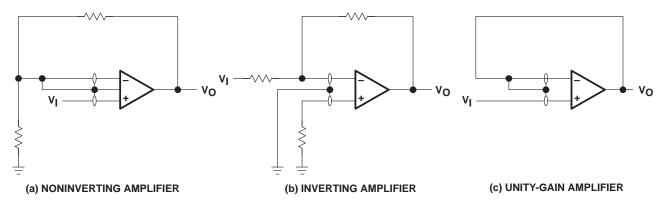


Figure 101. Guard-Ring Schemes

noise performance

The noise specifications in operational amplifiers circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias-current requirements of the TLV2341 results in a very low noise current, which is insignificant in most applications. This feature makes the device especially favorable over bipolar devices when using values of circuit impedance greater than 50 kΩ, since bipolar devices exhibit greater noise currents.

feedback

Operational amplifier circuits nearly always employ feedback, and since feedback is the first prerequisite for oscillation, caution is appropriate. Most oscillation problems result from driving capacitive loads and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 102). The value of this capacitor is optimized empirically.

electrostatic-discharge protection

The TLV2341 incorporates an internal electrostatic-discharge (ESD)-protection circuit that

Figure 102. Compensation for Input Capacitance

prevents functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2. Care should be exercised, however, when handling these devices as exposure to ESD may result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature dependent and have the characteristics of a reverse-biased diode.

latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLV2341 inputs and output are designed to withstand – 100-mA surge currents without sustaining latch-up; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal protection diodes should not by



APPLICATION INFORMATION

design be forward biased. Applied input and output voltage should not exceed the supply voltage by more that 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1 μ F typical) located across the supply rails as close to the device as possible.

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.

output characteristics

The output stage of the TLV2341 is designed to sink and source relatively high amounts of current (see Typical Characteristics). If the output is subjected to a short-circuit condition, this high-current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

Although the TLV2341 possesses excellent high-level output voltage and current capability. methods are available for boosting this capability if needed. The simplest method involves the use of a pullup resistor (Rp) connected from the output to the positive supply rail (see Figure 103). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on resistance between approximately 60 Ω and 180 Ω , depending on how hard the operational amplifier input is driven. With very low values of RP, a voltage offset from 0 V at the output occurs. Secondly, pullup resistor Rp acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.

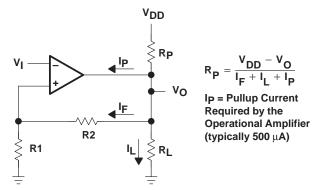


Figure 103. Resistive Pullup to Increase VOH

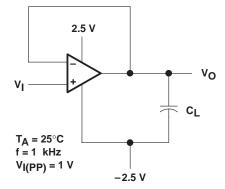


Figure 104. Test Circuit for Output Characteristics

All operating characteristics of the TLV2341 are measured using a 20-pF load. The device drives higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies thereby causing ringing, peaking, or even oscillation (see Figures 105, 106 and 107). In many cases, adding some compensation in the form of a series resistor in the feedback loop alleviates the problem.

APPLICATION INFORMATION

output characteristics (continued)

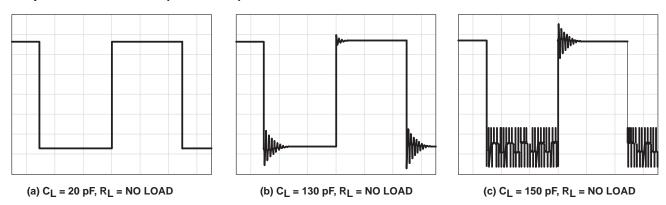


Figure 105. Effect of Capacitive Loads in High-Bias Mode

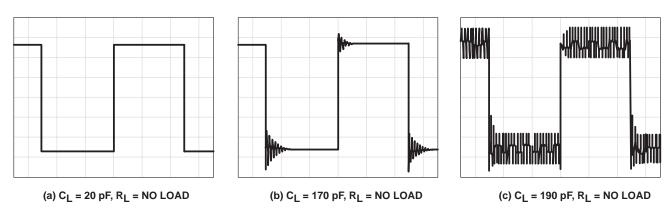


Figure 106. Effect of Capacitive Loads in Medium-Bias Mode

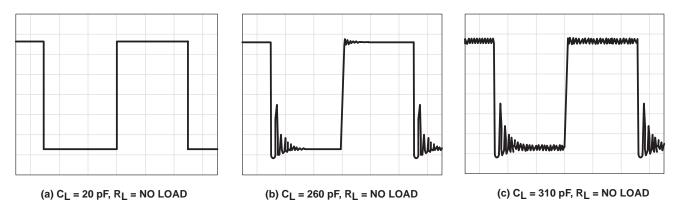


Figure 107. Effect of Capacitive Loads in Low-Bias Mode

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